

Notice of References Cited

Application/Control No.

10/541,093

Applicant(s)/Patent Under
Reexamination
FUJINE ET AL.

Examiner

ROBERT R. RAINEY

Art Unit

2629

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,095,393	08-2006	Lee, Baek-Woon	345/89
*	B	US-6,753,831	06-2004	Ide et al.	345/60
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NON-PATENT DOCUMENTS

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